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# PSMN8R5-100ES

N-channel 100 V 8.5 mΩ standard level MOSFET in I2PAK

11 October 2012

Product data sheet

## 1. Product profile

### 1.1 General description

Standard level N-channel MOSFET in a I2PAK package qualified to 175 °C. This product is designed and qualified for use in a wide range of industrial, communications and domestic equipment.

### 1.2 Features and benefits

- High efficiency due to low switching and conduction losses
- Suitable for standard level gate drive sources

### 1.3 Applications

- AC-to-DC power supply equipment
- Motor control
- Server power supplies
- Synchronous rectification

### 1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	100	V
I <sub>D</sub>	drain current	T <sub>j</sub> = 25 °C; V <sub>GS</sub> = 10 V; <a href="#">Fig. 1</a>	<a href="#">[1]</a>	-	-	100	A
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <a href="#">Fig. 2</a>		-	-	263	W
Static characteristics							
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; T <sub>j</sub> = 25 °C; <a href="#">Fig. 13</a> ; <a href="#">Fig. 12</a>		-	6.4	8.5	mΩ
Dynamic characteristics							
Q <sub>GD</sub>	gate-drain charge	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 25 A; V <sub>DS</sub> = 50 V; <a href="#">Fig. 14</a> ; <a href="#">Fig. 15</a>		-	33	-	nC
Q <sub>G(tot)</sub>	total gate charge			-	111	-	nC
Avalanche Ruggedness							
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	V <sub>GS</sub> = 10 V; T <sub>j(init)</sub> = 25 °C; I <sub>D</sub> = 100 A; V <sub>sup</sub> ≤ 100 V; R <sub>GS</sub> = 50 Ω; unclamped; <a href="#">Fig. 3</a>		-	-	219	mJ

[1] Continuous current limited by package.



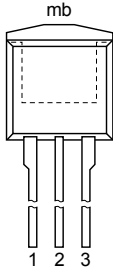
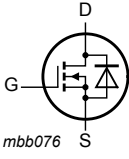
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## 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	 <p>I2PAK (SOT226)</p>	 <p>mbb076</p>
2	D	drain		
3	S	source		
mb	D	mounting base; connected to drain		

## 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PSMN8R5-100ES	I2PAK	plastic single-ended package (I2PAK); TO-262	SOT226

## 4. Marking

Table 4. Marking codes

Type number	Marking code
PSMN8R5-100ES	PSMN8R5-100ES

## 5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \geq 25\text{ °C}$ ; $T_j \leq 175\text{ °C}$		-	100	V
$V_{DGR}$	drain-gate voltage	$T_j \geq 25\text{ °C}$ ; $T_j \leq 175\text{ °C}$ ; $R_{GS} = 20\text{ k}\Omega$		-	100	V
$V_{GS}$	gate-source voltage			-20	20	V
$I_D$	drain current	$V_{GS} = 10\text{ V}$ ; $T_j = 25\text{ °C}$ ; Fig. 1	[1]	-	100	A
		$V_{GS} = 10\text{ V}$ ; $T_{mb} = 100\text{ °C}$ ; Fig. 1		-	75	A
$I_{DM}$	peak drain current	pulsed; $t_p \leq 10\text{ }\mu\text{s}$ ; $T_{mb} = 25\text{ °C}$ ; Fig. 4		-	429	A
$P_{tot}$	total power dissipation	$T_{mb} = 25\text{ °C}$ ; Fig. 2		-	263	W
$T_{stg}$	storage temperature			-55	175	°C

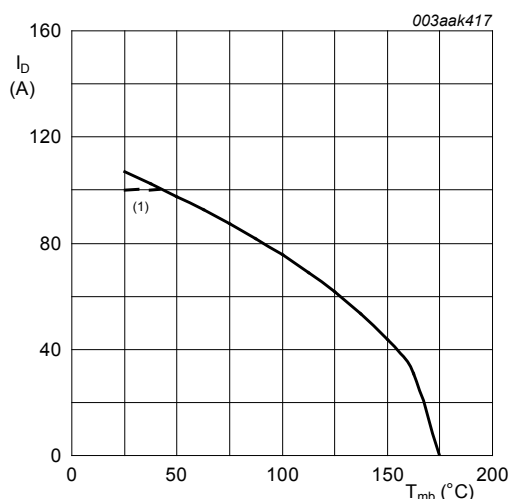
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Symbol	Parameter	Conditions		Min	Max	Unit
$T_j$	junction temperature			-55	175	°C
$T_{sld(M)}$	peak soldering temperature			-	260	°C
<b>Source-drain diode</b>						
$I_S$	source current	$T_{mb} = 25\text{ °C}$	[1]	-	100	A
$I_{SM}$	peak source current	pulsed; $t_p \leq 10\text{ }\mu\text{s}$ ; $T_{mb} = 25\text{ °C}$		-	429	A
<b>Avalanche Ruggedness</b>						
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	$V_{GS} = 10\text{ V}$ ; $T_{j(\text{init})} = 25\text{ °C}$ ; $I_D = 100\text{ A}$ ; $V_{sup} \leq 100\text{ V}$ ; $R_{GS} = 50\text{ }\Omega$ ; unclamped; <a href="#">Fig. 3</a>		-	219	mJ

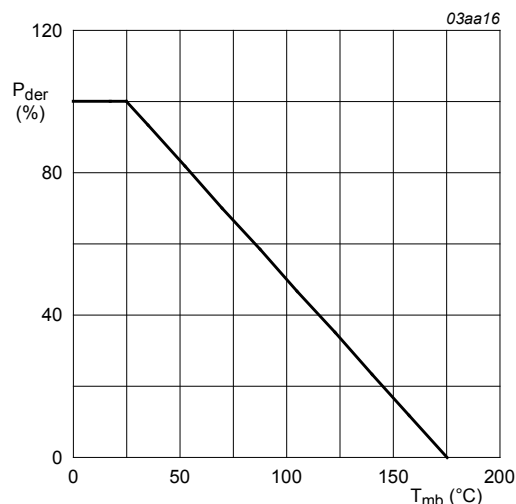
[1] Continuous current limited by package.



(1) Capped at 100A due to package

**Fig. 1. Continuous drain current as a function of mounting base temperature**

$$V_{GS} \geq 10V$$



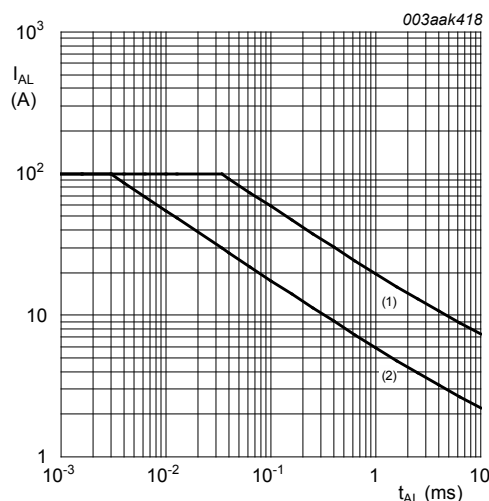
**Fig. 2. Normalized total power dissipation as a function of mounting base temperature**

$$P_{der} = \frac{P_{tot}}{P_{tot(25^\circ\text{C})}} \times 100\%$$

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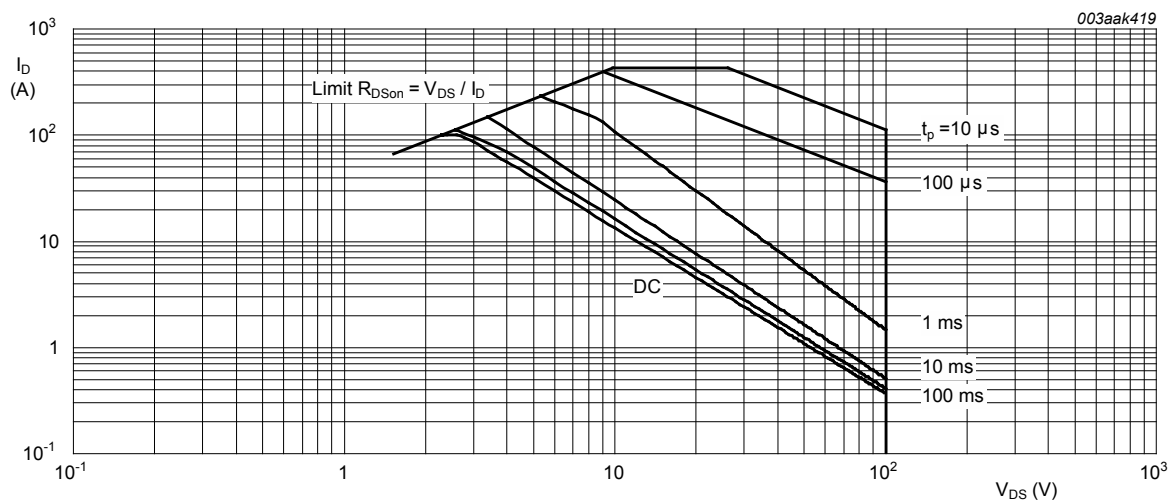
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**Fig. 3. Avalanche rating; avalanche current as a function of avalanche time**

(1)  $T_{j (init)} = 25^{\circ}\text{C}$ ; (2)  $T_{j (init)} = 130^{\circ}\text{C}$



**Fig. 4. Safe operating area; continuous and peak drain currents as a function of drain-source voltage**

$T_{mb} = 25^{\circ}\text{C}$ ;  $I_{DM}$  is a single pulse

## 6. Thermal characteristics

**Table 6. Thermal characteristics**

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	Fig. 5	-	0.49	0.57	K/W

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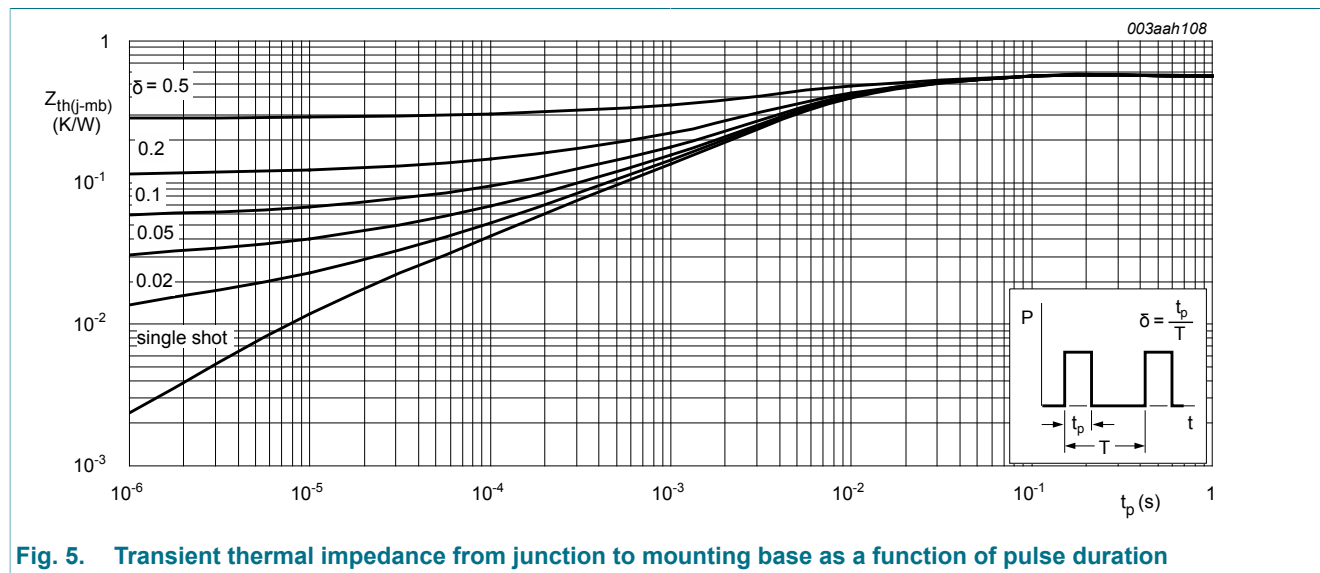


Fig. 5. Transient thermal impedance from junction to mounting base as a function of pulse duration

## 7. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Static characteristics</b>						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_J = 25 ^\circ C$	100	-	-	V
		$I_D = 250 \mu A; V_{GS} = 0 V; T_J = -55 ^\circ C$	90	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1 mA; V_{DS} = V_{GS}; T_J = 25 ^\circ C$ ; Fig. 10; Fig. 11	2.4	3	4	V
$V_{GSth}$	gate-source threshold voltage	$I_D = 1 mA; V_{DS} = V_{GS}; T_J = 175 ^\circ C$ ; Fig. 10	1	-	-	V
		$I_D = 1 mA; V_{DS} = V_{GS}; T_J = -55 ^\circ C$ ; Fig. 10	-	-	4.5	V
$I_{DSS}$	drain leakage current	$V_{DS} = 100 V; V_{GS} = 0 V; T_J = 25 ^\circ C$	-	0.02	1	$\mu A$
		$V_{DS} = 100 V; V_{GS} = 0 V; T_J = 100 ^\circ C$	-	-	20	$\mu A$
$I_{GSS}$	gate leakage current	$V_{GS} = -20 V; V_{DS} = 0 V; T_J = 25 ^\circ C$	-	2	100	nA
		$V_{GS} = 20 V; V_{DS} = 0 V; T_J = 25 ^\circ C$	-	2	100	nA
$R_{DSon}$	drain-source on-state resistance	$V_{GS} = 10 V; I_D = 25 A; T_J = 175 ^\circ C$ ; Fig. 12	-	-	22.6	mΩ
		$V_{GS} = 10 V; I_D = 25 A; T_J = 100 ^\circ C$ ; Fig. 12	-	-	14.9	mΩ
		$V_{GS} = 10 V; I_D = 25 A; T_J = 25 ^\circ C$ ; Fig. 13; Fig. 12	-	6.4	8.5	mΩ
$R_G$	gate resistance	$f = 1 MHz$	-	0.71	-	Ω

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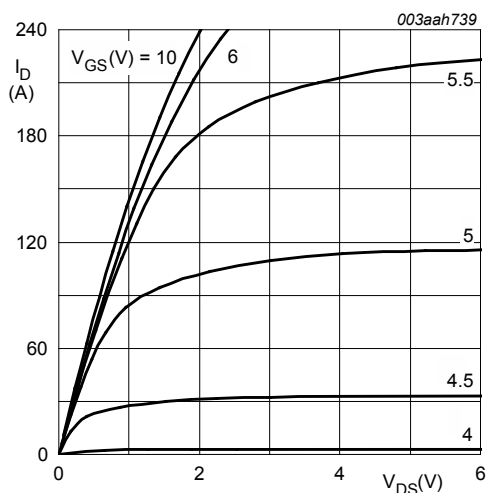
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Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Dynamic characteristics							
Q <sub>G(tot)</sub>	total gate charge	I <sub>D</sub> = 25 A; V <sub>DS</sub> = 50 V; V <sub>GS</sub> = 10 V; <a href="#">Fig. 14</a> ; <a href="#">Fig. 15</a>		-	111	-	nC
Q <sub>GS</sub>	gate-source charge			-	24	-	nC
Q <sub>GS(th)</sub>	pre-threshold gate-source charge			-	16	-	nC
Q <sub>GS(th-pl)</sub>	post-threshold gate-source charge			-	8	-	nC
Q <sub>GD</sub>	gate-drain charge			-	33	-	nC
V <sub>GS(pl)</sub>	gate-source plateau voltage	I <sub>D</sub> = 15 A; V <sub>DS</sub> = 50 V; <a href="#">Fig. 14</a> ; <a href="#">Fig. 15</a>		-	4.4	-	V
C <sub>iss</sub>	input capacitance	V <sub>DS</sub> = 50 V; V <sub>GS</sub> = 0 V; f = 1 MHz; T <sub>j</sub> = 25 °C; <a href="#">Fig. 16</a> ; <a href="#">Fig. 17</a>		-	5512	-	pF
C <sub>oss</sub>	output capacitance	V <sub>DS</sub> = 50 V; V <sub>GS</sub> = 0 V; f = 1 MHz; T <sub>j</sub> = 25 °C; <a href="#">Fig. 16</a>		-	380	-	pF
C <sub>rss</sub>	reverse transfer capacitance	V <sub>DS</sub> = 50 V; V <sub>GS</sub> = 0 V; f = 1 MHz; T <sub>j</sub> = 25 °C; <a href="#">Fig. 16</a> ; <a href="#">Fig. 17</a>		-	256	-	pF
t <sub>d(on)</sub>	turn-on delay time	V <sub>DS</sub> = 50 V; R <sub>L</sub> = 2 Ω; V <sub>GS</sub> = 10 V; R <sub>G(ext)</sub> = 5 Ω		-	20	-	ns
t <sub>r</sub>	rise time			-	35	-	ns
t <sub>d(off)</sub>	turn-off delay time			-	87	-	ns
t <sub>f</sub>	fall time			-	43	-	ns
Source-drain diode							
V <sub>SD</sub>	source-drain voltage	I <sub>S</sub> = 25 A; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C; <a href="#">Fig. 18</a>		-	0.82	1.2	V
t <sub>rr</sub>	reverse recovery time	I <sub>S</sub> = 25 A; dI <sub>S</sub> /dt = -100 A/μs; V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 50 V		-	53	-	ns
Q <sub>r</sub>	recovered charge			-	124	-	nC

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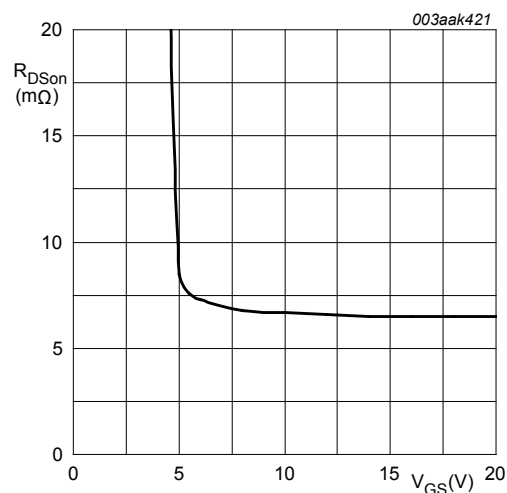
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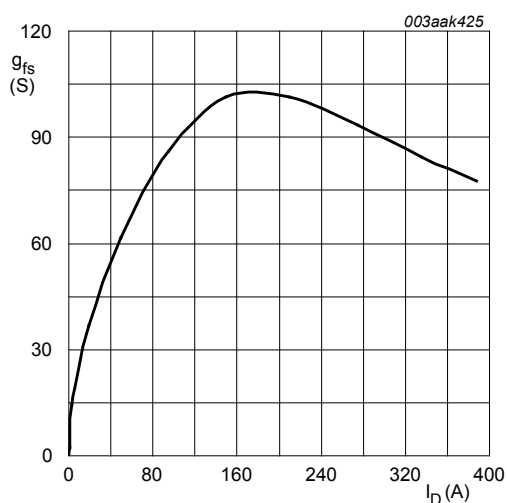
$T_j = 25^\circ\text{C}$ ;  $t_p = 300\ \mu\text{s}$

**Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values**



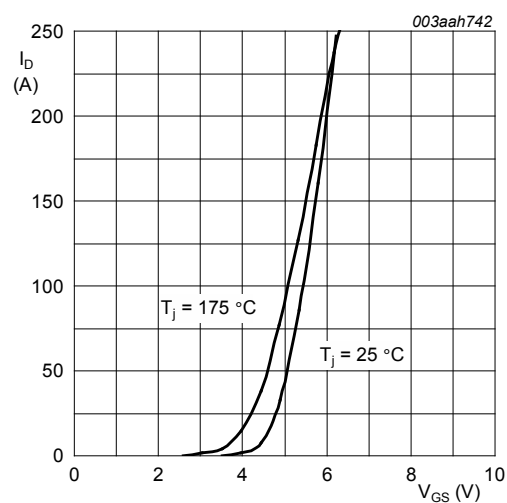
**Fig. 7. Drain-source on-state resistance as a function of gate-source voltage; typical values**

$T_j = 25^\circ\text{C}$ ;  $I_D = 25\text{A}$



**Fig. 8. Forward transconductance as a function of drain current; typical values**

$T_j = 25^\circ\text{C}$ ;  $V_{DS} = 10\text{V}$



**Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values**

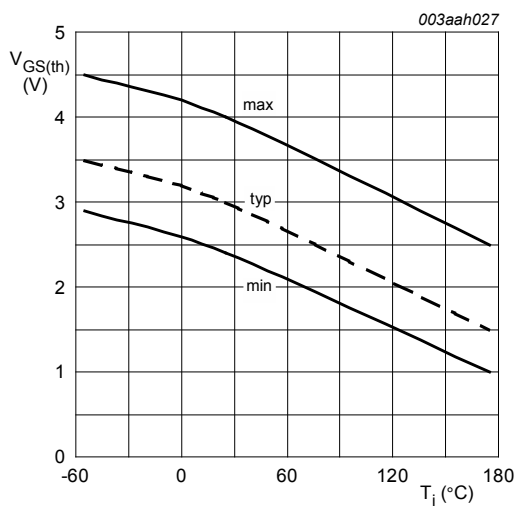
$V_{DS} = 10\text{V}$



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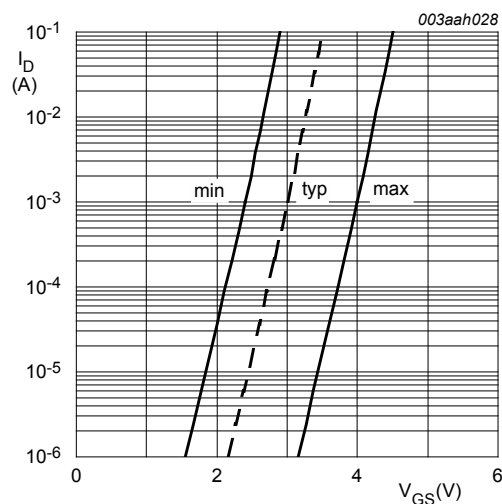
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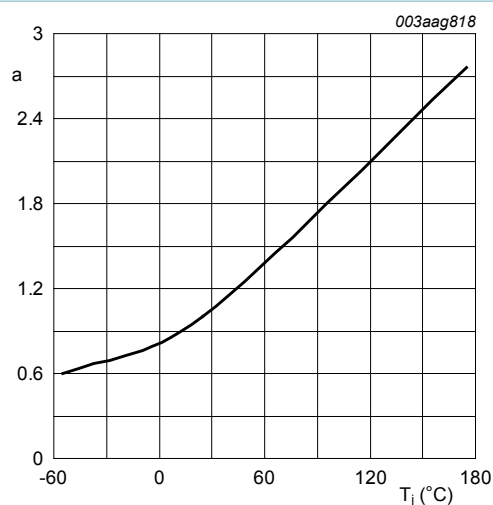
**Fig. 10. Gate-source threshold voltage as a function of junction temperature**

$$I_D = 1 \text{ mA}; V_{DS} = V_{GS}$$



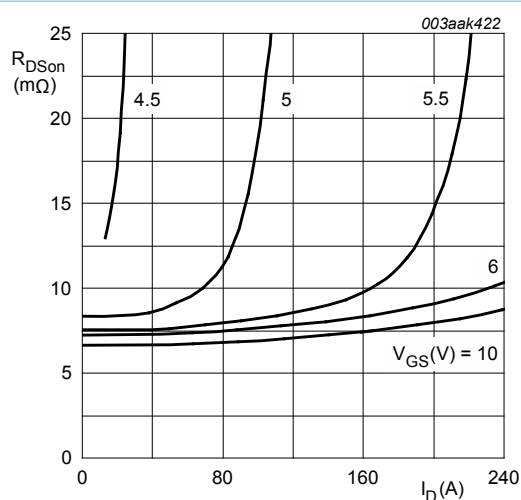
**Fig. 11. Sub-threshold drain current as a function of gate-source voltage**

$$T_j = 25^\circ\text{C}; V_{DS} = 5\text{V}$$



**Fig. 12. Normalized drain-source on-state resistance factor as a function of junction temperature**

$$a = \frac{R_{DSon}}{R_{DSon(25^\circ\text{C})}}$$



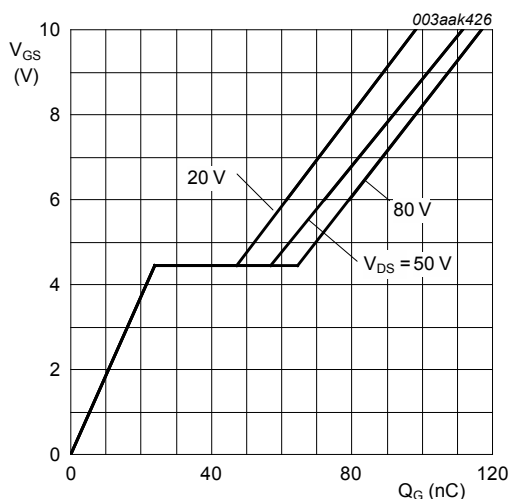
**Fig. 13. Drain-source on-state resistance as a function of drain current; typical values**

$$T_j = 25^\circ\text{C}$$

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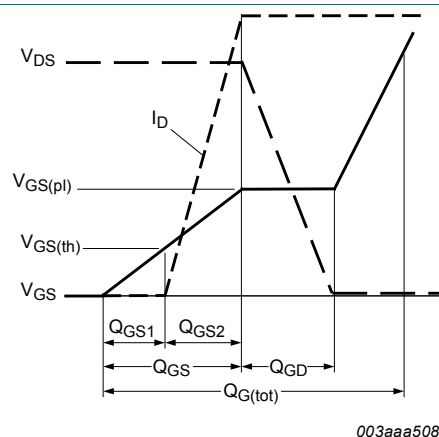
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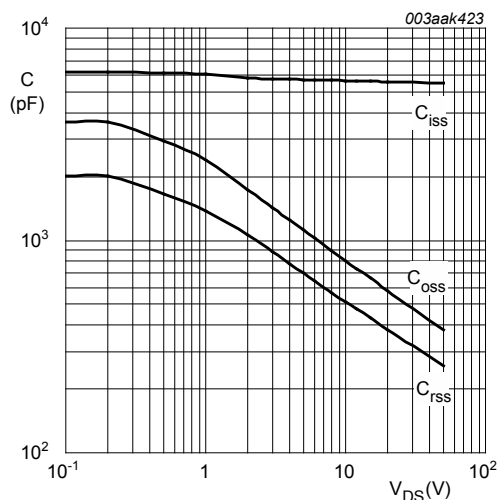


**Fig. 14. Gate-source voltage as a function of gate charge; typical values**

$T_j = 25^\circ\text{C}; I_D = 25\text{ A}$

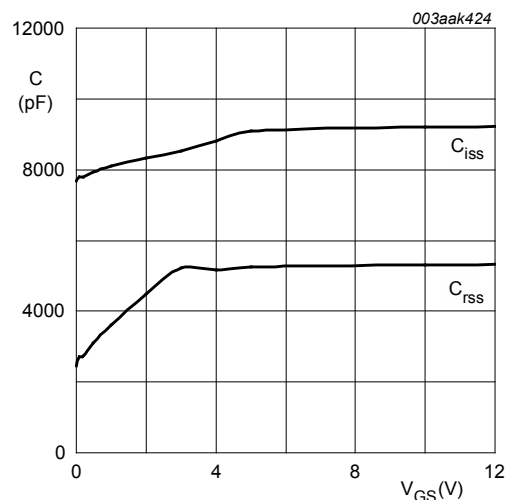


**Fig. 15. Gate charge waveform definitions**



**Fig. 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values**

$V_{GS} = 0\text{ V}; f = 1\text{ MHz}$



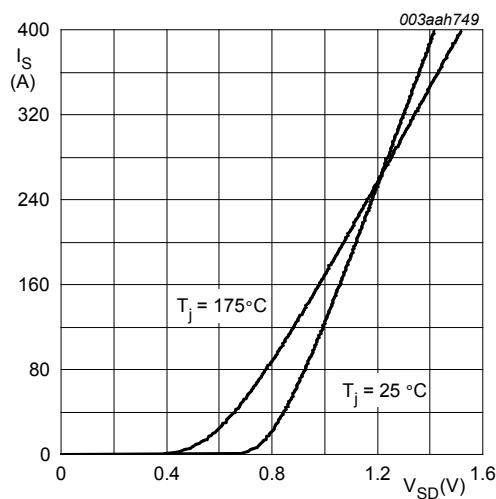
**Fig. 17. Input and reverse transfer capacitances as a function of gate-source voltage, typical values**

$f = 1\text{ MHz}; V_{DS} = 0\text{ V}$

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**Fig. 18. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values**

$$V_{GS} = 0V$$

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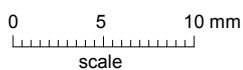
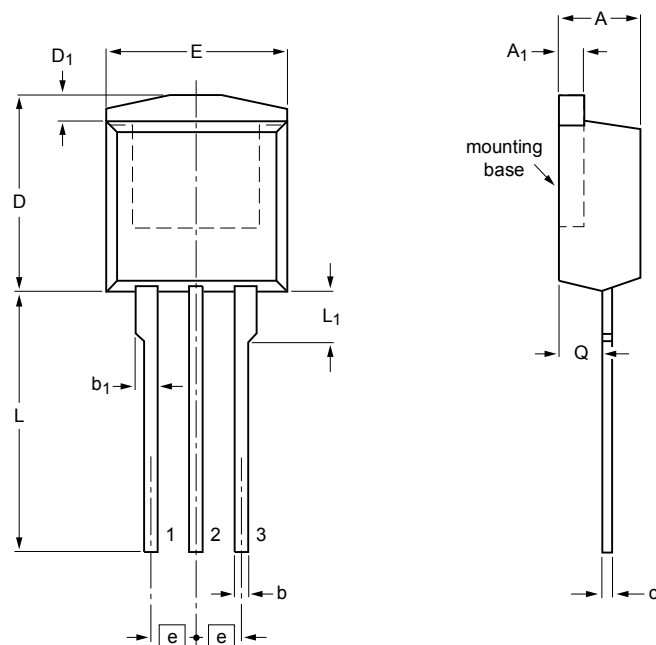
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### 8. Package outline

Plastic single-ended package (I2PAK); low-profile 3-lead TO-262

SOT226



DIMENSIONS (mm are the original dimensions)

UNIT	A	A <sub>1</sub>	b	b <sub>1</sub>	c	D <sub>max</sub>	D <sub>1</sub>	E	e	L	L <sub>1</sub>	Q
mm	4.5 4.1	1.40 1.27	0.85 0.60	1.3 1.0	0.7 0.4	11	1.6 1.2	10.3 9.7	2.54	15.0 13.5	3.30 2.79	2.6 2.2

OUTLINE VERSION	REFERENCES				EUROPEAN PROJECTION	ISSUE DATE
	IEC	JEDEC	JEITA			
SOT226		TO-262				-06-02-14 09-08-25

Fig. 19. Package outline I2PAK (SOT226)

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### N-channel 100 V 8.5 mΩ standard level MOSFET in I2PAK

## 9. Legal information

### 9.1 Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.  
 [2] The term 'short data sheet' is explained in section "Definitions".  
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## PSMN8R5-100ES

### N-channel 100 V 8.5 mΩ standard level MOSFET in I2PAK

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